


<b>Search Notes</b>  	<b>Application/Control No.</b>  10564164	<b>Applicant(s)/Patent Under Reexamination</b>  MIYAJI ET AL.
	<b>Examiner</b>  Tran Nguyen	<b>Art Unit</b>  2834

SEARCHED			
Class	Subclass	Date	Examiner
310	64, 6868D	4/12/08	/TN/
363	123, 125, 126, 144, 145	4/12/08	/TN/

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner